1365 Adams Court, Menlo Park, CA 94025

Tellus Technology., Model No: WipClip-V131C Date of Test: May 25 to June 2, 2001

6.0 DOCUMENT HISTORY

Revision/ Job Number	Writer Initials	Date	Change
1.0 /J20051521	SS	June 7, 2001	Original document

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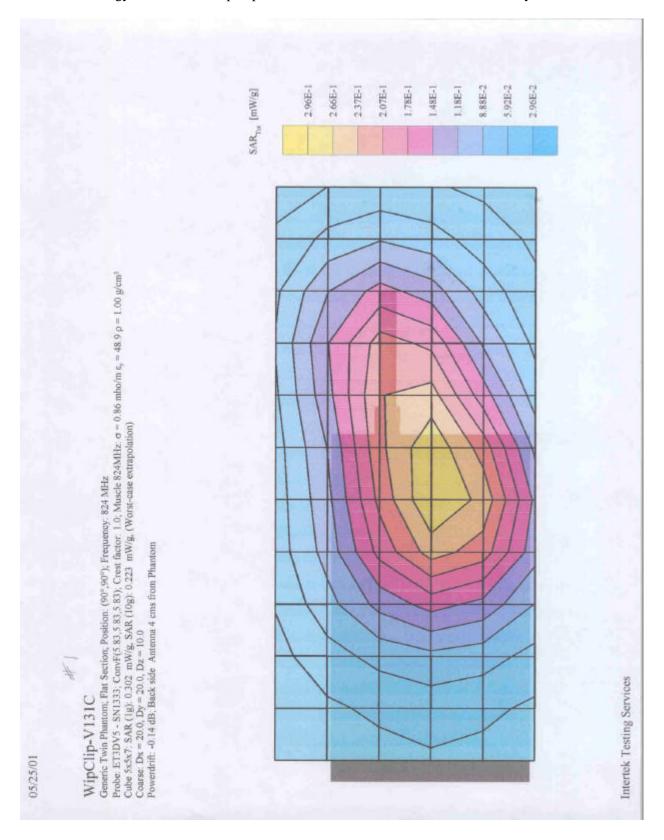
APPENDIX A - SAR Evaluation Data

File: 20515211

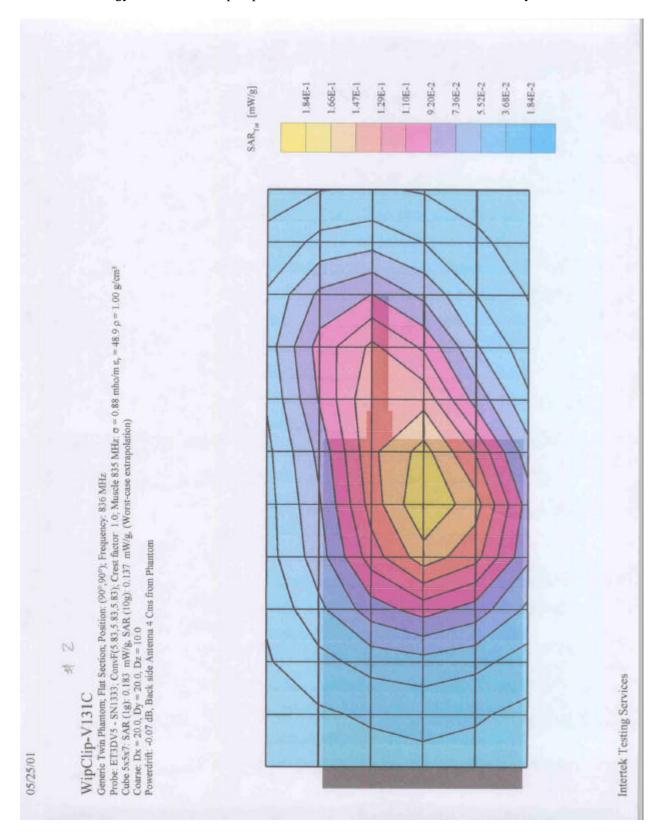
Please note that the graphical visualization of the phone position onto the SAR distribution gives only limited information on the current distribution of the device, since the curvature of the head results in graphical distortion. Full information can only be obtained either by H-field scans in free space or SAR evaluation with a flat phantom.

Power drift is the measurement of power drift of the device over one complete SAR scan.

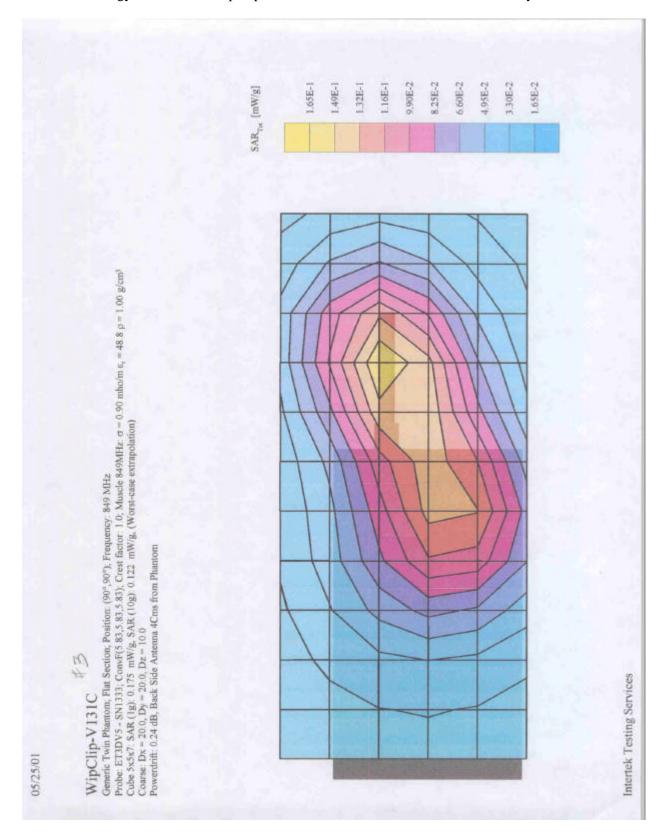
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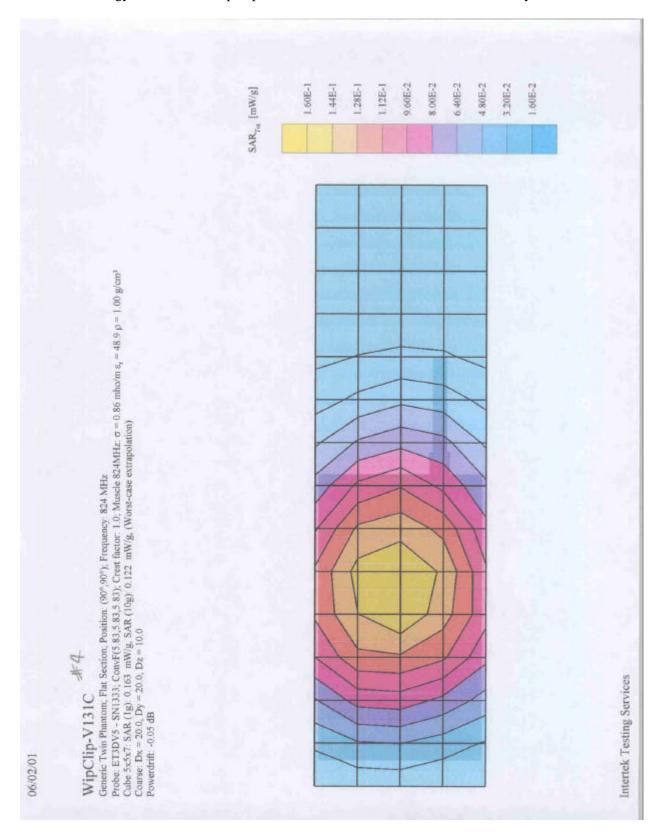
Date of Test: May 25 to June 2, 2001



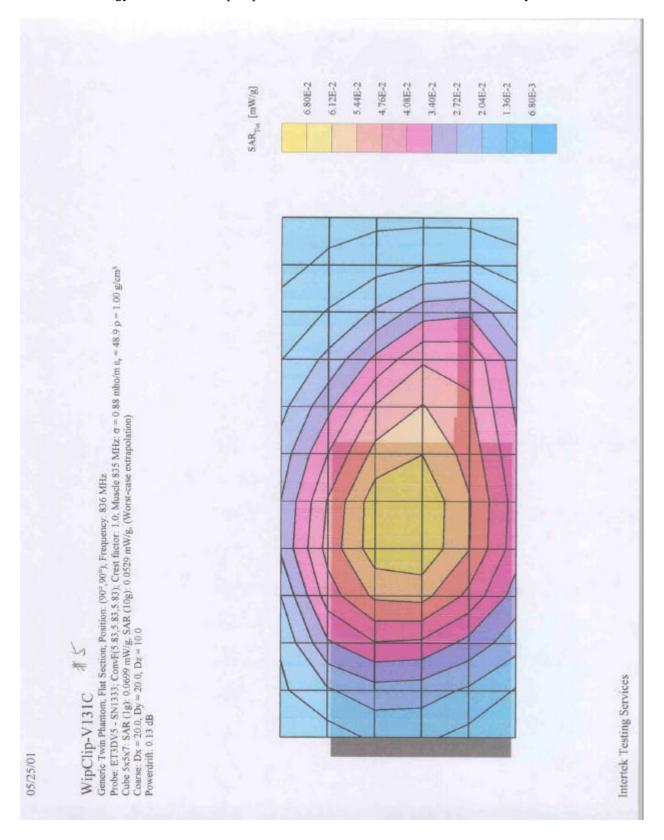
Date of Test: May 25 to June 2, 2001



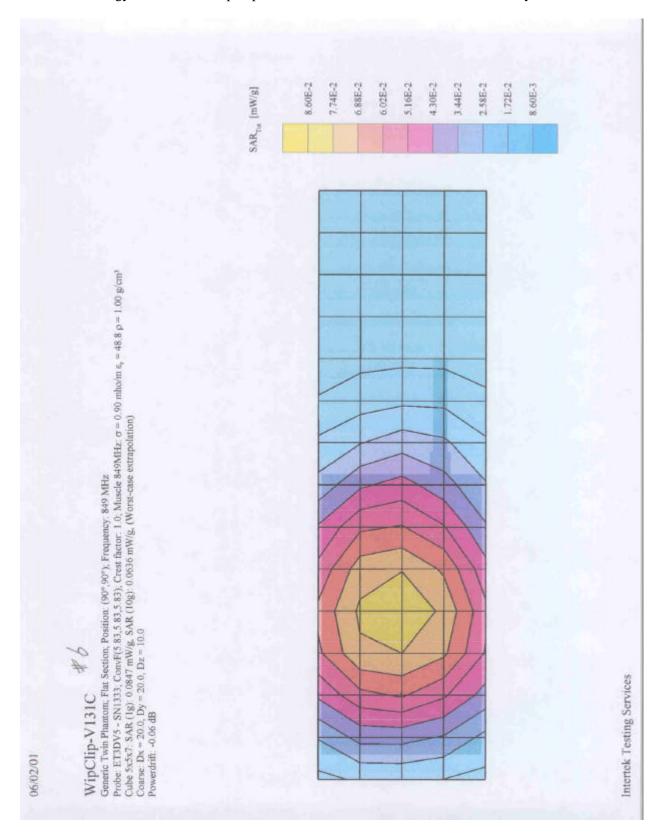
Date of Test: May 25 to June 2, 2001



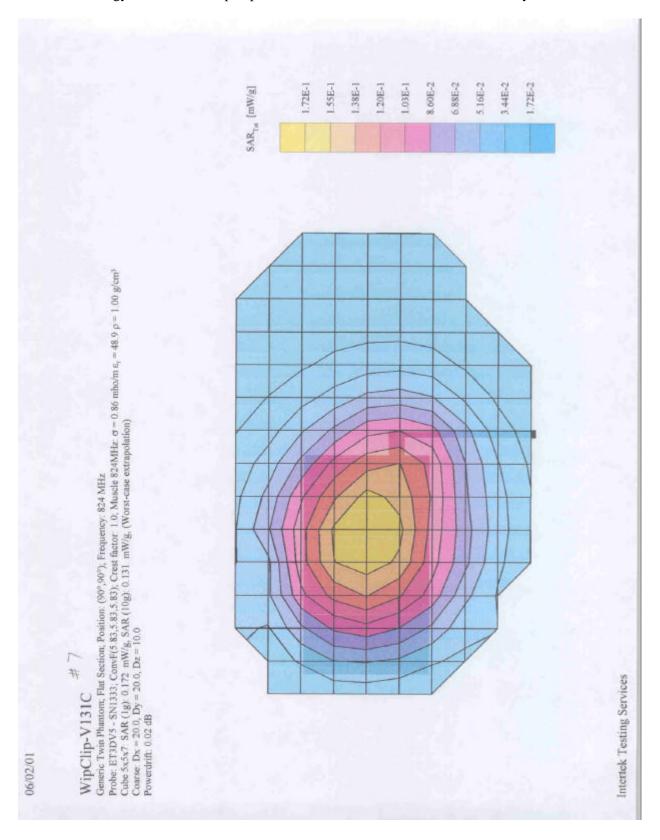
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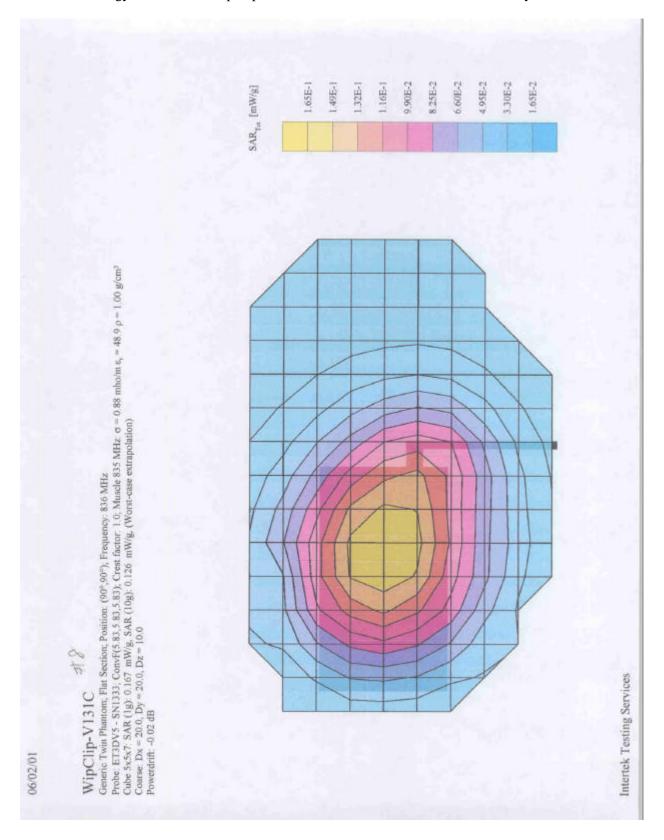
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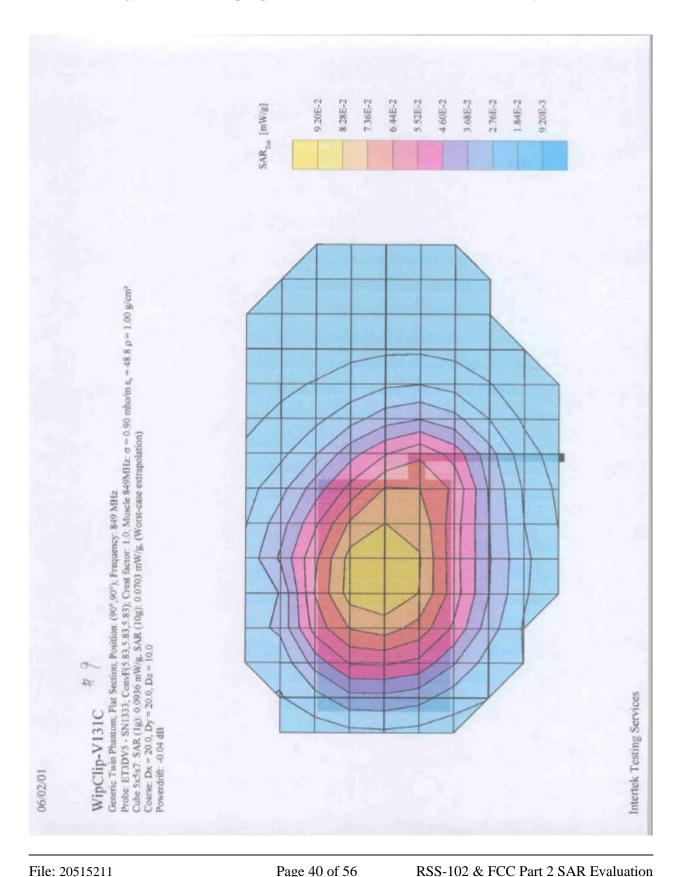


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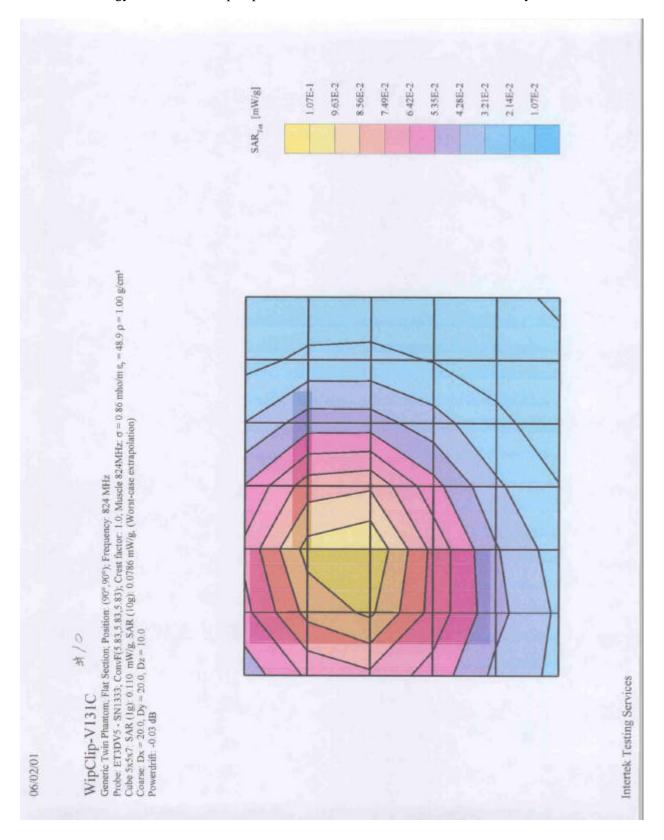


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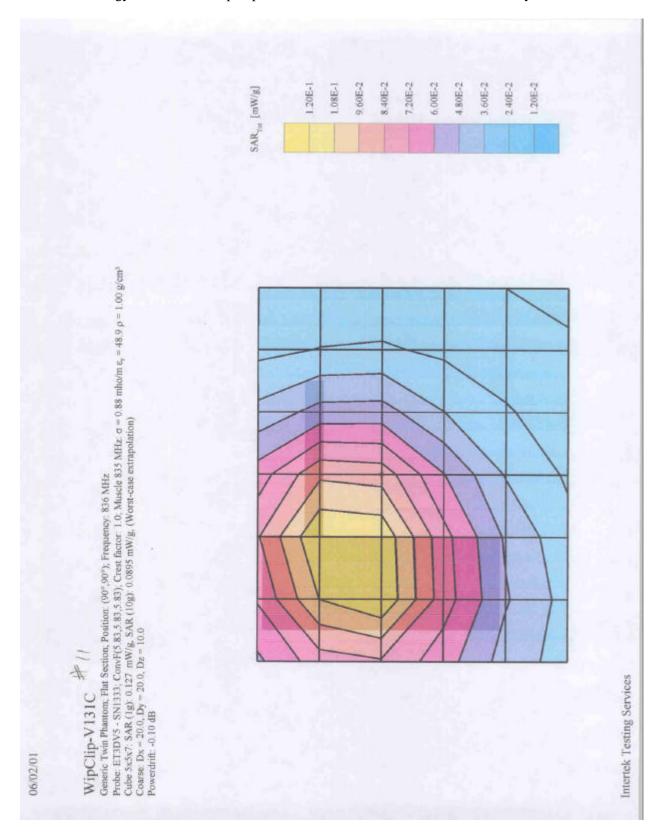




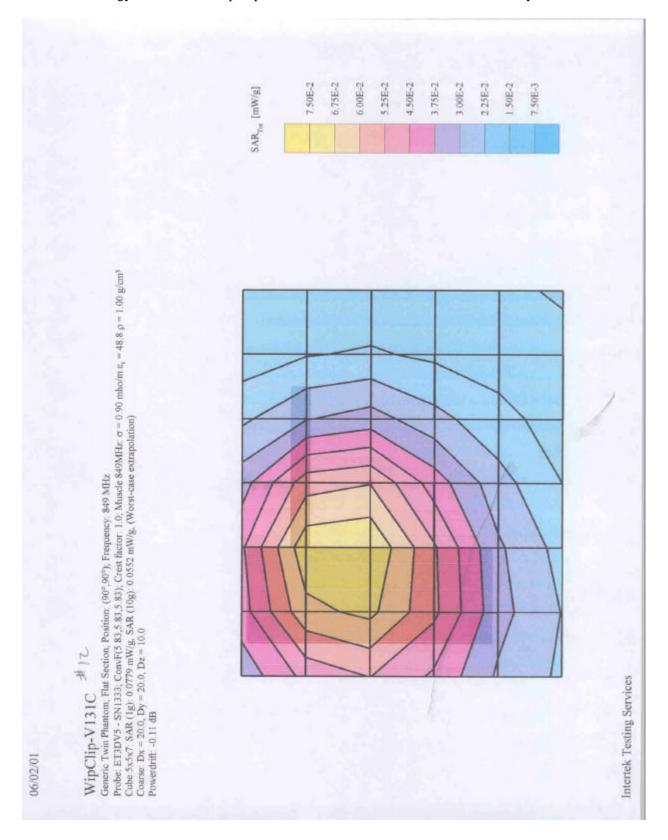
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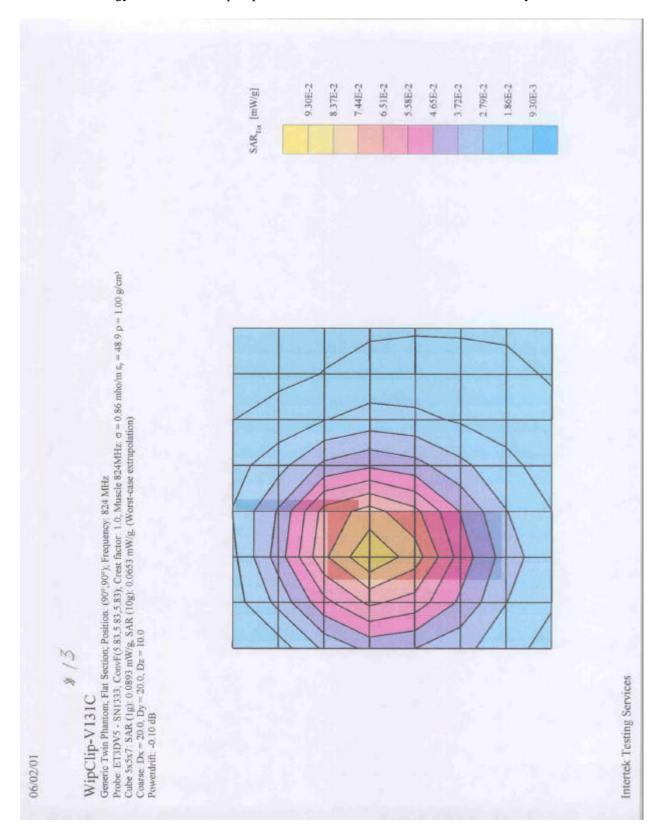
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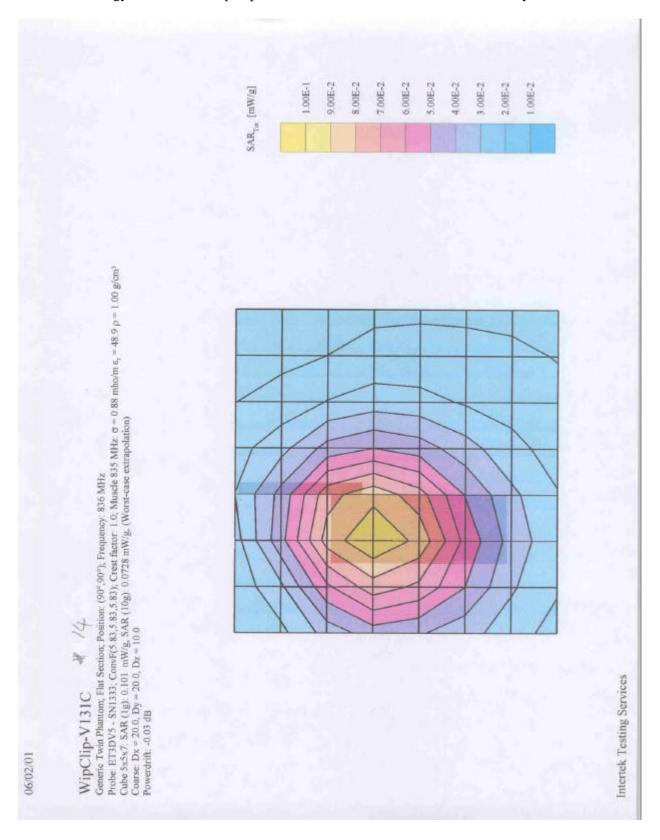
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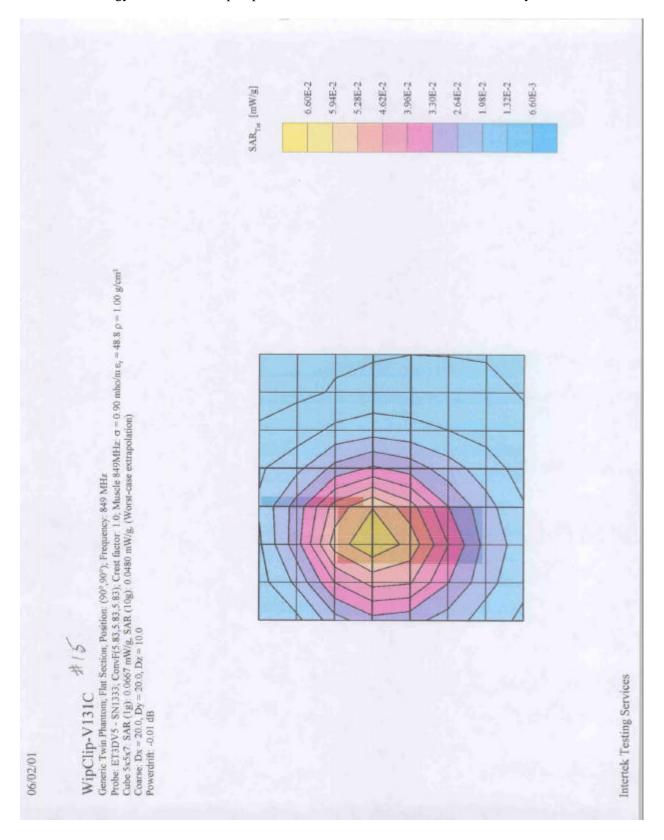
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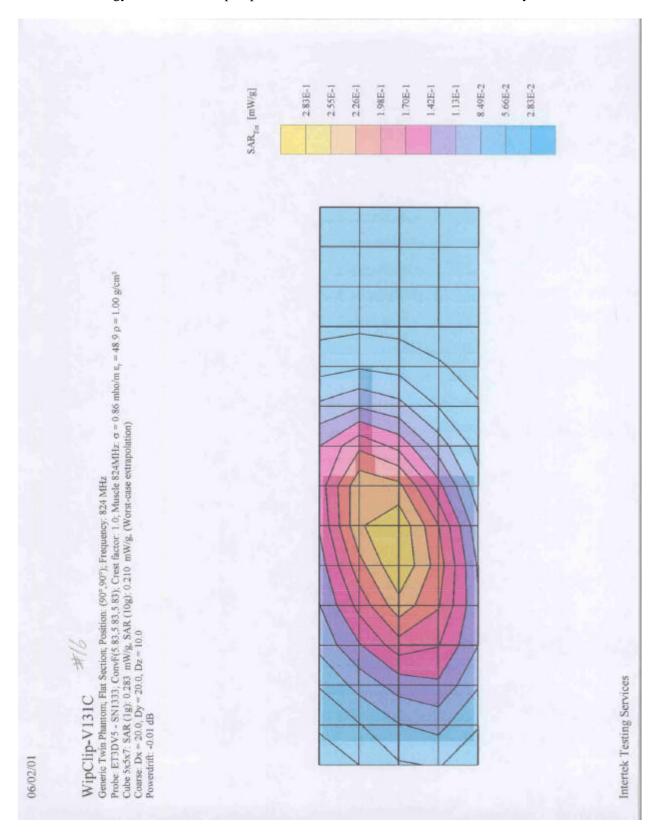
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APPENDIX B - E-Field Probe Calibration Data

See attached.



Date of Test: May 25 to June 2, 2001

Schmid & Partner Engineering AG

Zeughausstrasse 43, 8004 Zurich, Switzerland, Phone +41 1 245 97 00, Fax +41 1 245 97 79

Calibration Certificate

Dosimetric E-Field Probe

Type: ET3DV5 Serial Number: 1333 Place of Calibration: Zurich Date of Calibration: April 23, 2001 Calibration Interval: 12 months

Schmid & Partner Engineering AG hereby certifies, that this device has been calibrated on the date indicated above. The calibration was performed in accordance with specifications and procedures of Schmid & Partner Engineering AG.

Wherever applicable, the standards used in the calibration process are traceable to international standards. In all other cases the standards of the Laboratory for EMF and Microwave Electronics at the Swiss Federal Institute of Technology (ETH) in Zurich, Switzerland have been applied.

Calibrated by:

Short Neviana Approved by:

Date of Test: May 25 to June 2, 2001

Schmid & Partner Engineering AG

Zeughausstrasse 43, 8004 Zurich, Switzerland, Telephone +41 1 245 97 00, Fax +41 1 245 97 79

Probe ET3DV5

SN:1333

Manufactured:

December 20, 1997

Last calibration:

April 10, 2000

Recalibrated:

April 23, 2001

Calibrated for System DASY3

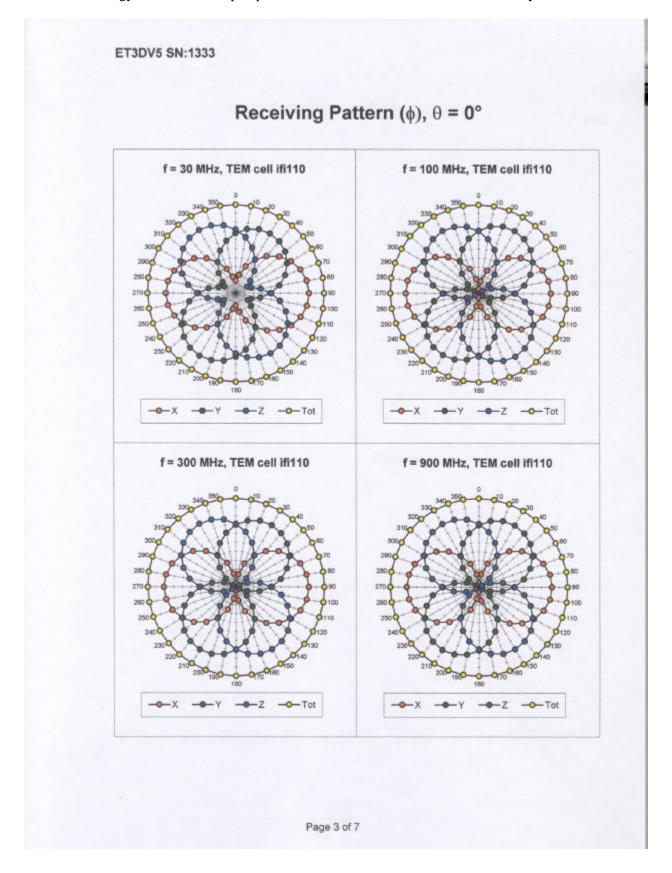
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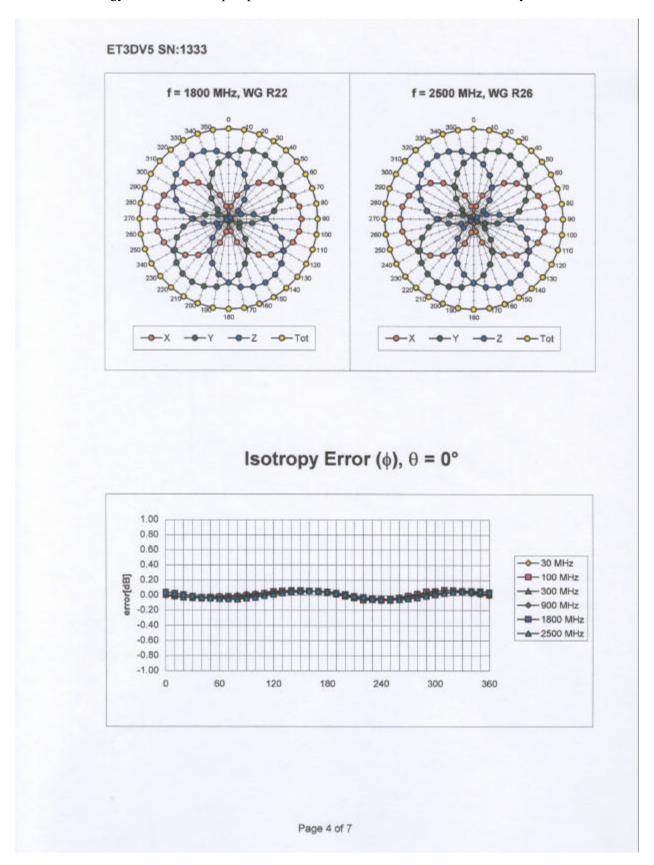
File: 20515211

DAS	Y3 - Para	amete	ers of Probe	: ET3DV5 SI	N:1333	
Sensi	tivity in Free	Space		Diode Compre	ssion	
	NormX	2.37	$\mu V/(V/m)^2$	DCP X	100 m\	
	NormY	2.38	$\mu V/(V/m)^2$	DCPY	100 m\	
	NormZ	2.33	$\mu V/(V/m)^2$	DCP Z	100 m\	
Sensi	tivity in Tiss	ue Simi	ulating Liquid			
Head	450 MHz		$\epsilon_{\rm r}$ = 43.5 ± 5%	$\sigma = 0.87 \pm 10$	= 0.87 ± 10% mho/m	
	ConvF X	6.25	extrapolated	Boundary	effect:	
	ConvF Y	6.25	extrapolated	Alpha	0.19	
	ConvF Z	6.25	extrapolated	Depth	3.06	
Head	900 MHz		$\varepsilon_{\rm r}$ = 42 ± 5%	$\sigma = 0.97 \pm 10$	σ = 0.97 ± 10% mho/m	
	ConvF X 5.83		± 7% (k=2)	Boundary	Boundary effect:	
	ConvF Y	5.83	± 7% (k=2)	Alpha	0.38	
	ConvF Z	5.83	± 7% (k=2)	Depth	2.70	
Brain	1500 N	lHz	ϵ_r = 41 ± 5%	σ = 1.32 ± 10	% mho/m	
	ConvF X	5.27	interpolated	Boundary	y effect:	
	ConvF Y	5.27	interpolated	Alpha	0.63	
	ConvF Z	5.27	interpolated	Depth	2.23	
Brain	1800 MHz		ϵ_r = 41 ± 5%	$\sigma = 1.69 \pm 10$	σ = 1.69 ± 10% mho/m	
	ConvF X	4.99	± 7% (k=2)	Boundary	y effect:	
	ConvF Y	4.99	± 7% (k=2)	Alpha	0.75	
	ConvF Z	4.99	± 7% (k=2)	Depth	1.99	
Senso	or Offset					
	Probe Tip to Sensor Center			2.7	mm	
	Optical Surfa	ce Detect	ion	1.6 ± 0.2	mm	

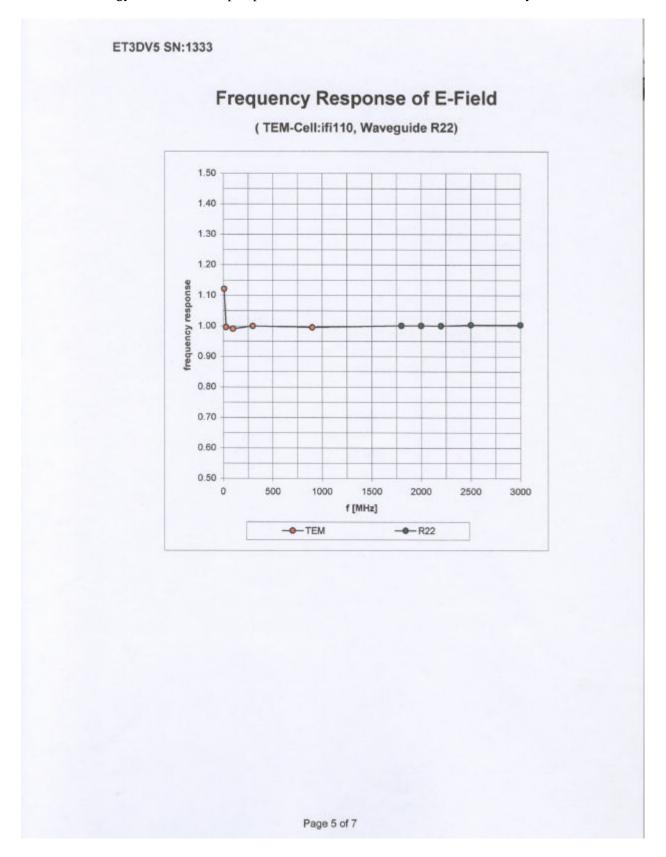
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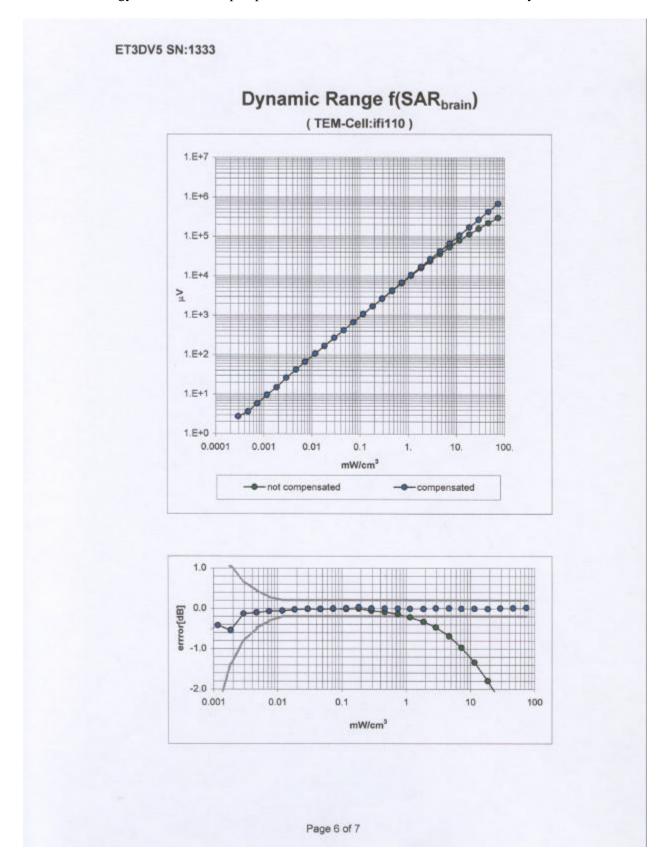
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